Application/Control No. O9/449,625 Reexamination OGAWA, HIROSHI Examiner Shun Lee Applicant(s)/Patent Under Reexamination OGAWA, HIROSHI Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,728,583 A	03-1988	Yamazaki et al.	428/690
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	D	US-			
	Ε	US-			
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NON-PATENT DOCUMENTS

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